# **5-Channel ESD Protection** Array

## **Product Description**

The PACDN009 is a diode array designed to provide 5 channels of ESD protection for electronic components or sub–systems. Each channel consists of a pair of diodes which steers an ESD current pulse to either the positive (V<sub>P</sub>) or negative (V<sub>N</sub>) supply. The PACDN009 protects against ESD pulses up to  $\pm 15$  kV Human Body Model (100 pF capacitor discharging through a 1.5 k $\Omega$  resistor), and  $\pm 8$  kV contact discharge, per International Standard IEC 61000–4–2.

This device is particularly well–suited for portable electronics (e.g., cellular phones, PDAs, notebook computers) because of its small package footprint, high ESD protection level, and low loading capacitance. It is also suitable for protecting video output lines and I/O ports in computers and peripherals and is ideal for a wide range of consumer electronics products.

The PACDN009 is supplied in an 8-lead MSOP package and is available with RoHS compliant lead-free finishing.

#### Features

- Five Channels of ESD Protection
- ±8 kV Contact, ±15 kV Air ESD Protection per Channel (IEC 61000-4-2 Standard)
- ±15 kV of ESD Protection per Channel (HBM)
- Low Loading Capacitance (3 pF Typical)
- Low Leakage Current is Ideal for Battery-Powered Devices
- Available in Miniature 8–Pin MSOP Package
- These Devices are Pb-Free and are RoHS Compliant

#### Applications

- Consumer Electronic Products
- Cellular Phones
- PDAs
- Notebook Computers
- Desktop PCs
- Digital Cameras and Camcorders
- VGA (Video) Port Protection for Desktop and Portable PCs



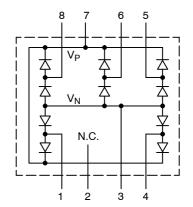
# **ON Semiconductor®**

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MSOP 8 MR SUFFIX CASE 846AB

**ELECTRICAL SCHEMATIC** 



### MARKING DIAGRAM



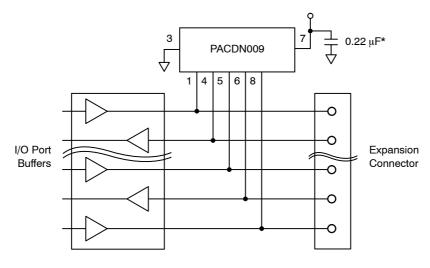
009R = PACDN009MR

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
PACDN009MR	MSOP 8 (Pb–Free)	4000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

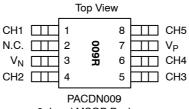
## TYPICAL APPLICATION CIRCUIT



Handheld/PDA ESD Protection

\* Capacitor should be placed as close as possible to Pin7.

## PACKAGE / PINOUT DIAGRAMS



8-Lead MSOP Package

#### Table 1. PIN DESCRIPTIONS

Pin	Name	Туре	Description
1	CH1	I/O	ESD Channel
2	N.C.	-	No Connect
3	V <sub>N</sub>	GND	Negative Voltage Supply Rail or Ground Reference Rail
4	CH2	I/O	ESD Channel
5	СНЗ	I/O	ESD Channel
6	CH4	I/O	ESD Channel
7	V <sub>P</sub>	Supply	Positive Voltage Supply Rail
8	CH5	I/O	ESD Channel

### **SPECIFICATIONS**

### Table 2. ABSOLUTE MAXIMUM RATINGS

Parameter	Rating	Units	
Supply Voltage (V <sub>P</sub> - V <sub>N</sub> )	6.0	V	
Diode Forward DC Current (Note 1)	20	mA	
Operating Temperature Range	-40 to +85	°C	
Storage Temperature Range	-65 to +150	°C	
DC Voltage at any Channel Input	(V <sub>N</sub> – 0.5) to (V <sub>P</sub> + 0.5)	V	
Package Power Rating	200	mW	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. Only one diode conducting at a time.

#### **Table 3. STANDARD OPERATING CONDITIONS**

Parameter	Rating	Units
Operating Temperature Range	-40 to +85	°C
Operating Supply Voltage (V <sub>P</sub> - V <sub>N</sub> )	0 to 5.5	V

#### Table 4. ELECTRICAL OPERATING CHARACTERISTICS (Note 1)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
Ι <sub>Ρ</sub>	Supply Current	(V <sub>P</sub> – V <sub>N</sub> ) = 5.5 V			10	μA
VF	Diode Forward Voltage	I <sub>F</sub> = 20 mA	0.65		0.95	V
I <sub>LEAK</sub>	Channel Leakage Current			±0.1	±1.0	μΑ
C <sub>IN</sub>	Channel Input Capacitance	@ 1 MHz, V <sub>P</sub> = 5 V, V <sub>N</sub> = 0 V, V <sub>IN</sub> = 2.5 V (Note 2)		3	5	pF
V <sub>ESD</sub>	ESD Protection Peak Discharge Voltage at any Channel Input, in System a) Human Body Model, MIL-STD-883, Method 3015 b) Contact Discharge per IEC 61000-4-2 c) Air Discharge per IEC 61000-4-2	(Note 2) (Note 3) (Note 4) (Note 4)	±15 ±8 ±15			kV
V <sub>CL</sub>	Channel Clamp Voltage Positive Transients Negative Transients	@ 15 kV ESD HBM			V <sub>P</sub> + 13.0 V <sub>N</sub> - 13.0	V

1. All parameters specified at  $T_A = 25^{\circ}C$  unless otherwise noted.  $V_P = 5 \text{ V}$ ,  $V_N = 0 \text{ V}$  unless noted. 2. From I/O pins to  $V_P$  or  $V_N$  only.  $V_P$  bypassed to  $V_N$  with a 0.22  $\mu$ F ceramic capacitor (see Application Information for more details). 3. Human Body Model per MIL–STD–883, Method 3015,  $C_{\text{Discharge}} = 100 \text{ pF}$ ,  $R_{\text{Discharge}} = 1.5 \text{ k}\Omega$ ,  $V_P = 5.0 \text{ V}$ ,  $V_N$  grounded. 4. Standard IEC 61000–4–2 with  $C_{\text{Discharge}} = 150 \text{ pF}$ ,  $R_{\text{Discharge}} = 330 \Omega$ ,  $V_P = 5.0 \text{ V}$ ,  $V_N$  grounded.

#### **PERFORMANCE INFORMATION**

#### Input Capacitance vs. Input Voltage

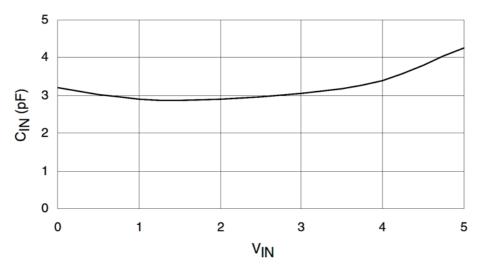


Figure 1. Typical Variation of C<sub>IN</sub> vs. V<sub>IN</sub> (V<sub>P</sub> = 5 V, V<sub>N</sub> = 0 V, 0.1  $\mu F$  Chip Capacitor between V<sub>P</sub> and V<sub>N</sub>)

#### **APPLICATION INFORMATION**

#### **Design Considerations**

In order to realize the maximum protection against ESD pulses, care must be taken in the PCB layout to minimize parasitic series inductances on the Supply/Ground rails as well as the signal trace segment between the signal input (typically a connector) and the ESD protection device. Refer to Figure 2, which illustrates an example of a positive ESD pulse striking an input channel. The parasitic series inductance back to the power supply is represented by  $L_1$  and  $L_2$ . The voltage  $V_{CL}$  on the line being protected is:

$$V_{CL} = Fwd Voltage Drop of D_1 + V_{SUPPLY} + L_1 \times d(I_{ESD})/dt + L_2 \times d(I_{ESD})/dt$$

where I<sub>ESD</sub> is the ESD current pulse, and V<sub>SUPPLY</sub> is the positive supply voltage.

An ESD current pulse can rise from zero to its peak value in a very short time. As an example, a level 4 contact discharge per the IEC61000–4–2 standard results in a current pulse that rises from zero to 30 Amps in 1 ns. Here  $d(I_{ESD})/dt$  can be approximated by  $\Delta I_{ESD}/\Delta t$ , or 30/(1x10<sup>-9</sup>). So just 10 nH of series inductance (L<sub>1</sub> and L<sub>2</sub> combined) will lead to a 300 V increment in V<sub>CL</sub>!

Similarly for negative ESD pulses, parasitic series inductance from the  $V_N$  pin to the ground rail will lead to drastically increased negative voltage on the line being protected.

Another consideration is the output impedance of the power supply for fast transient currents. Most power supplies exhibit a much higher output impedance to fast transient current spikes. In the  $V_{CL}$  equation above, the  $V_{SUPPLY}$  term, in reality, is given by ( $V_{DC} + I_{ESD} \times R_{OUT}$ ), where  $V_{DC}$  and  $R_{OUT}$  are the nominal supply DC output voltage and effective output impedance of the power supply respectively. As an example, a  $R_{OUT}$  of 1  $\Omega$  would result in a 10 V increment in  $V_{CL}$  for a peak  $I_{ESD}$  of 10 A.

If the inductances and resistance described above are close to zero, the rail–clamp ESD protection diodes will do a good job of protection. However, since this is not possible in practical situations, a bypass capacitor must be used to absorb the very high frequency ESD energy. So for any brand of rail–clamp ESD protection diodes, a bypass capacitor should be connected between the V<sub>P</sub> pin of the diodes and the ground plane (V<sub>N</sub> pin of the diodes) as shown in the Application Circuit diagram below. A value of 0.22  $\mu$ F is adequate for IEC–61000–4–2 level 4 contact discharge protection (±8 kV). Ceramic chip capacitors mounted with short printed circuit board traces are good choices for this application. Electrolytic capacitors should be avoided as they have poor high frequency characteristics. For extra protection, connect a zener diode in parallel with the bypass capacitor to mitigate

the effects of the parasitic series inductance inherent in the capacitor. The breakdown voltage of the zener diode should be slightly higher than the maximum supply voltage.

As a general rule, the ESD Protection Array should be located as close as possible to the point of entry of expected electrostatic discharges. The power supply bypass capacitor mentioned above should be as close to the  $V_P$  pin of the Protection Array as possible, with minimum PCB trace lengths to the power supply, ground planes and between the signal input and the ESD device to minimize stray series inductance.

### **Additional Information**

See also ON Semiconductor Application Notes AP209, "Design Considerations for ESD Protection" and AP219, "ESD Protection for USB 2.0 Systems".

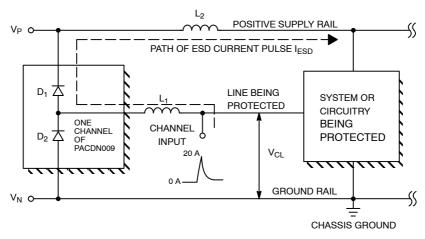
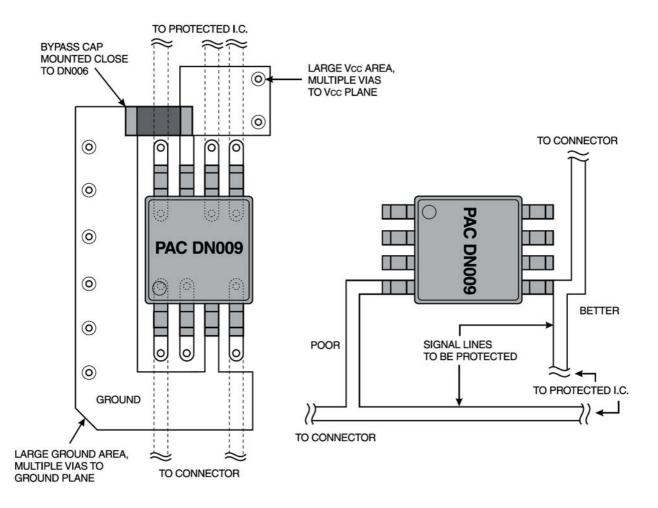
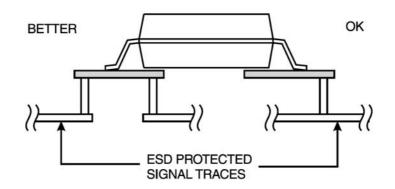


Figure 2. Application of Positive ESD Pulse between Input Channel and Ground

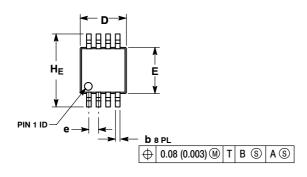


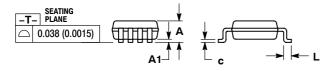




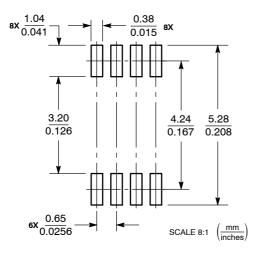
#### PACKAGE DIMENSIONS

MSOP8 CASE 846AB-01 **ISSUE O** 





#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

- 2
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE 3. BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
- DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE. 4. 5

846A-01 OBSOLETE, NEW STANDARD 846A-02.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α			1.10			0.043
A1	0.05	0.08	0.15	0.002	0.003	0.006
b	0.25	0.33	0.40	0.010	0.013	0.016
С	0.13	0.18	0.23	0.005	0.007	0.009
D	2.90	3.00	3.10	0.114	0.118	0.122
E	2.90	3.00	3.10	0.114	0.118	0.122
е	0.65 BSC				0.026 BSC	)
L	0.40	0.55	0.70	0.016	0.021	0.028
HE	4.75	4.90	5.05	0.187	0.193	0.199

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